

Silicon N-Channel Power MOSFET

Description

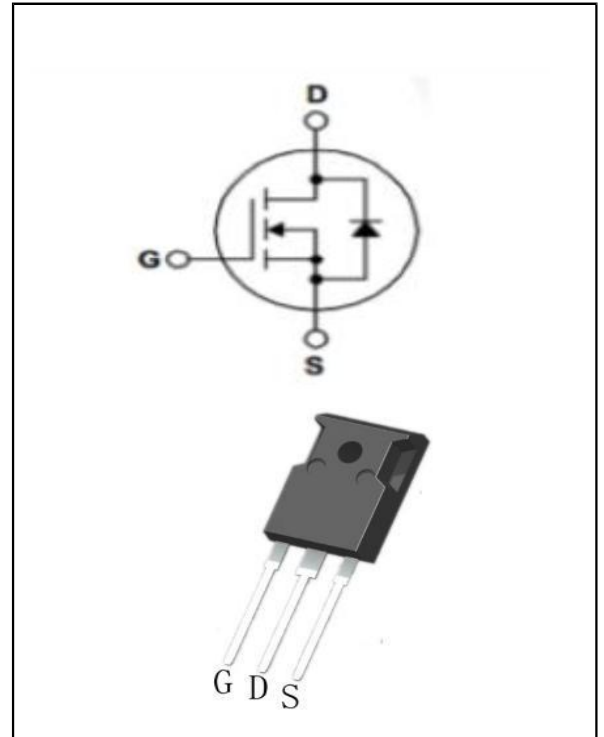
The MD200N08 uses advanced technology and design to provide excellent $R_{DS(ON)}$. It can be used in a wide variety of applications.

General Features

- ① $V_{DS} = 80V, I_D = 200A, R_{DS(ON)} < 4m\Omega @ V_{GS}=10V$
- ② High density cell design for lower R_{dson}
- ③ Fully characterized avalanche voltage and current
- ④ Good stability and uniformity with high EAS
- ⑤ Excellent package for good heat dissipation

Application

- ① Power Switching application
- ② Hard switched and High frequency circuits
- ③ Uninterruptible power supply



Package Marking And Ordering Information:

Ordering Codes	Package	Product Code	Packing
MD200N08	TO-247	MD200N08	Tube

Absolute Maximum Ratings @ $T_a=25^\circ C$ (unless otherwise specified)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	80	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current-Continuous	I_D	200	A
Drain Current-Pulsed ^(Note 1)	I_{DM}	800	A
Maximum Power Dissipation($T_c=25^\circ C$)	P_D	270	W
Single pulse avalanche energy ^(Note 2)	E_{AS}	1600	mJ
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 175	$^\circ C$

Thermal Characteristic

Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.41	$^\circ C/W$
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Electrical Characteristics (TA=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Typ	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =250μA	80	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =80V, V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
On Characteristics						
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250μA	2	3	4	V
Drain-Source On-State Resistance ^(Note 3)	R _{DS(ON)}	V _{GS} =10V, I _D =50A	-	3.5	4	mΩ
Forward Transconductance	g _{FS}	V _{DS} =5V, I _D =15A	-	17	-	S
Dynamic Characteristics						
Input Capacitance	C _{iss}	V _{DS} =25V, V _{GS} =0V, f=1.0MHz	-	13200	-	pF
Output Capacitance	C _{oss}		-	-950	-	pF
Reverse Transfer Capacitance	C _{rss}		-	810	-	pF
Switching Characteristics ^(Note 4)						
Turn-on Delay Time	t _{d(on)}	V _{DD} =40V, I _D =40A, V _{GS} =10V, R _{GEN} =3Ω	-	26	-	nS
Turn-on Rise Time	t _r		-	20	-	nS
Turn-Off Delay Time	t _{d(off)}		-	50	-	nS
Turn-Off Fall Time	t _f		-	18	-	nS
Total Gate Charge	Q _g	V _{DS} =64V, I _D =80A V _{GS} =10V	-	257	-	nC
Gate-Source Charge	Q _{gs}		-	76	-	nC
Gate-Drain Charge	Q _{gd}		-	80	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage	V _{SD}	V _{GS} =0V, I _S =80A	-	-	1.2	V

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. E_{AS} condition : T_j=25°C, V_{DD}=50V, V_G=10V, L=0.5mH, R_g=1Ω
3. Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.
4. Guaranteed by design, not subject to production

Characteristics Curves

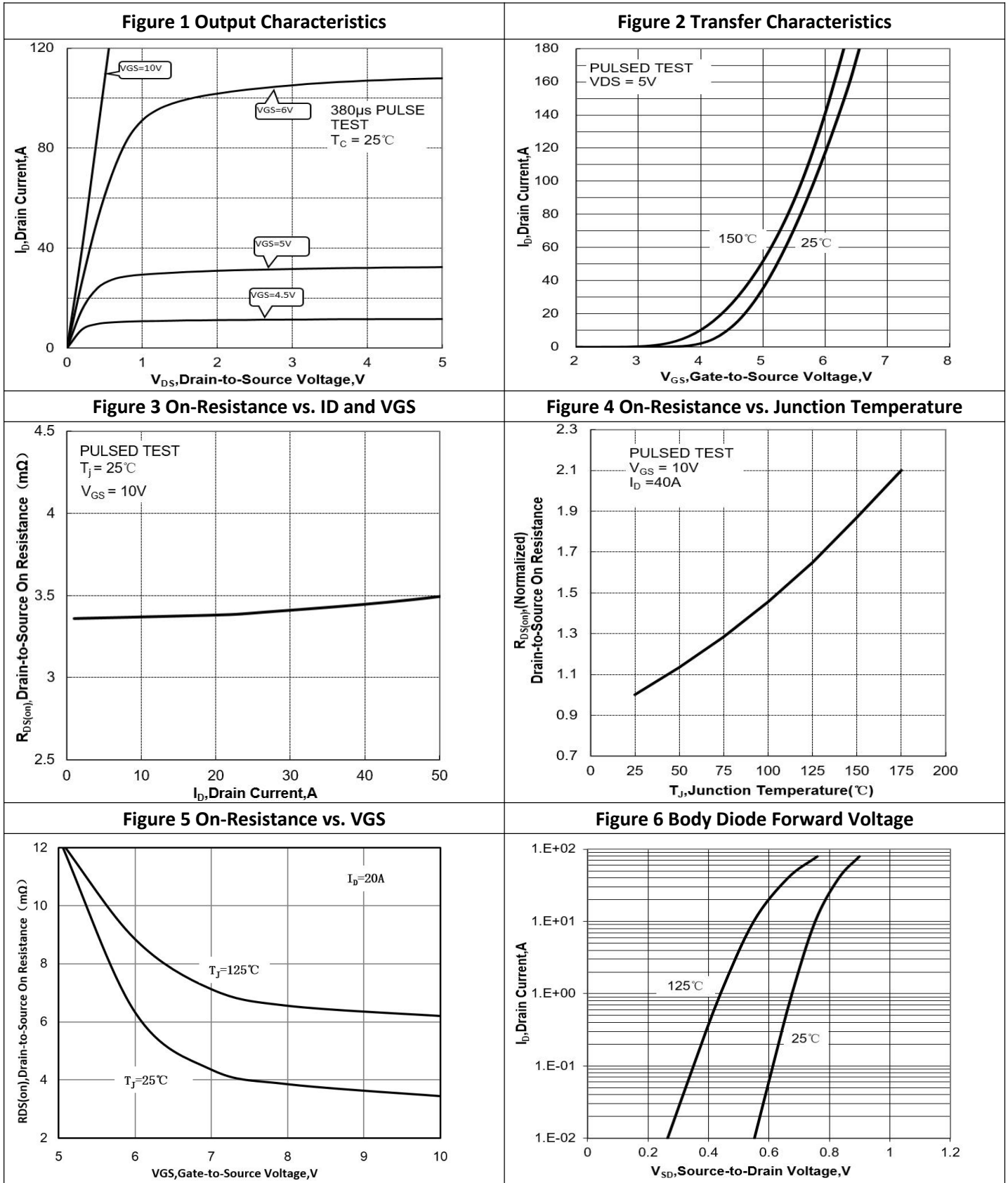


Figure 7 Gate-Charge Characteristics

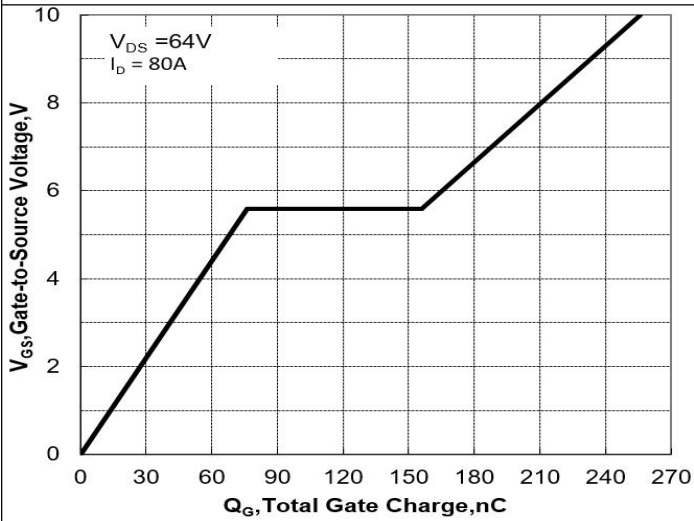


Figure 8 Capacitance Characteristics

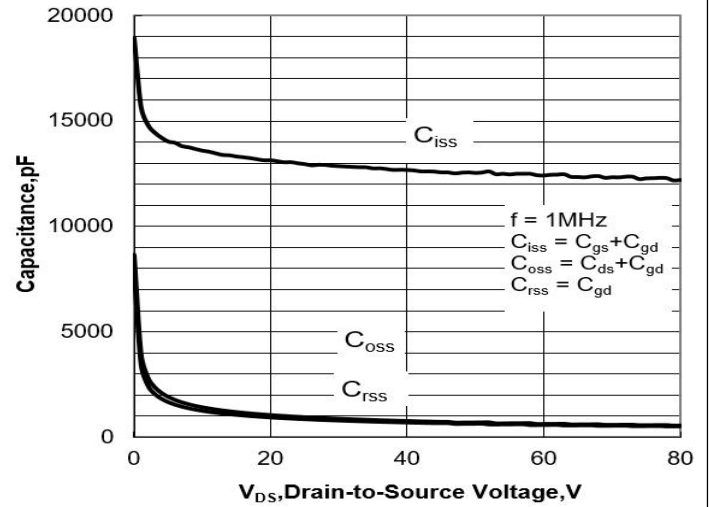


Figure 9 Maximum Forward Biased Safe Operation Area

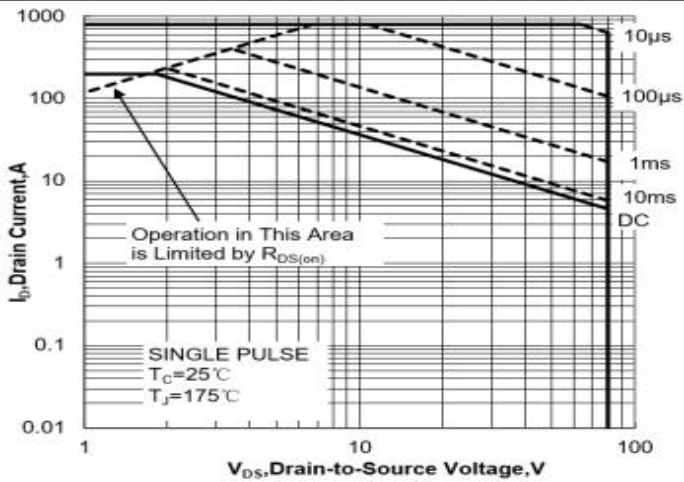


Figure 10 Single Pulse Power Rating Junction-to-Ambient

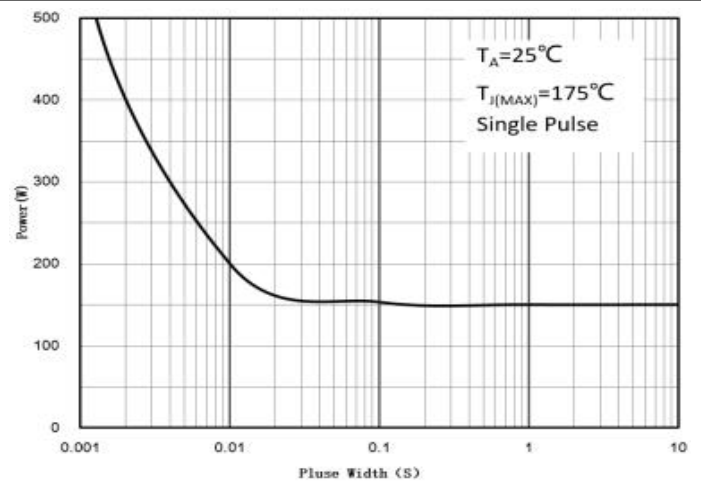
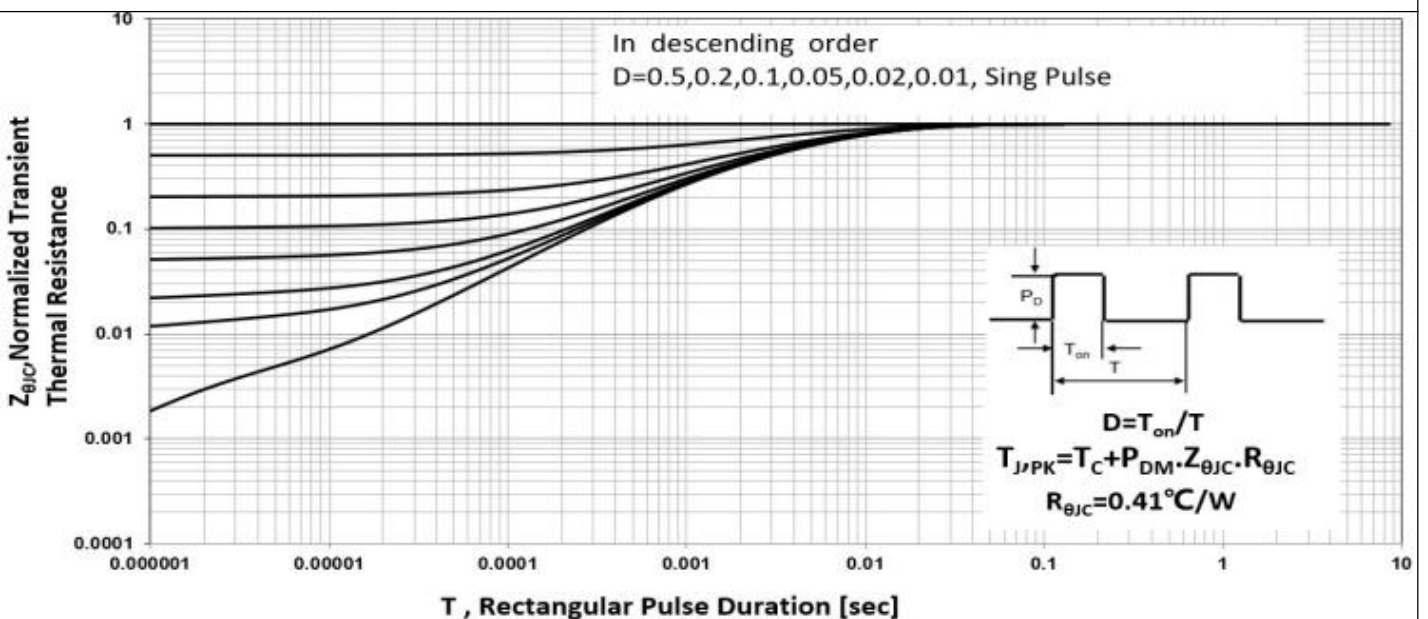
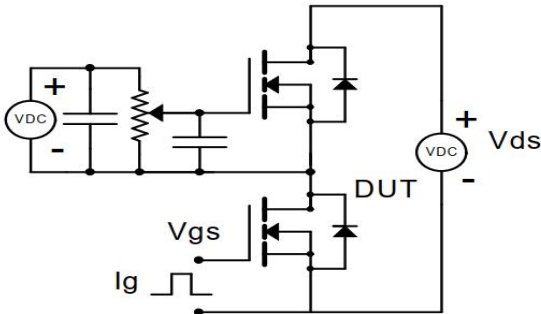
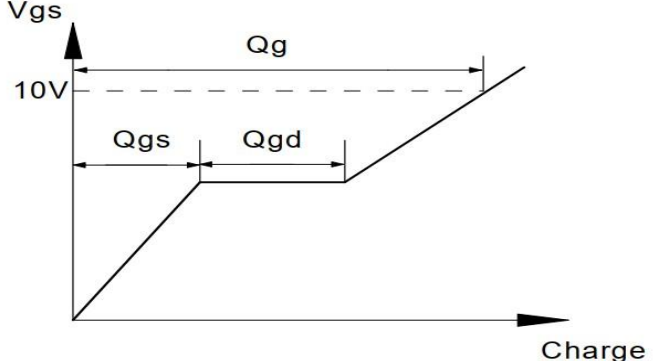
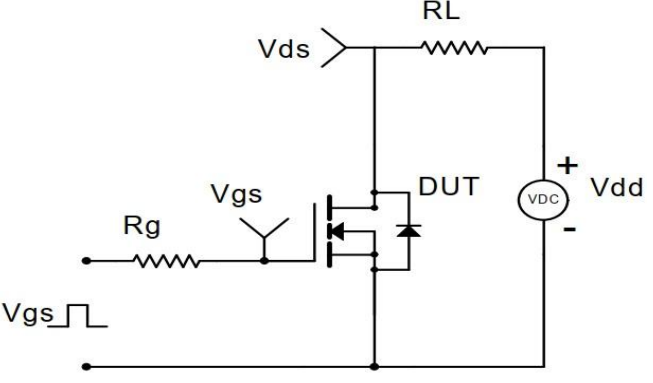
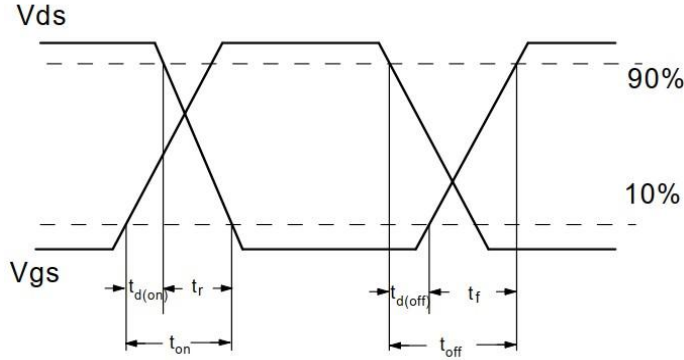
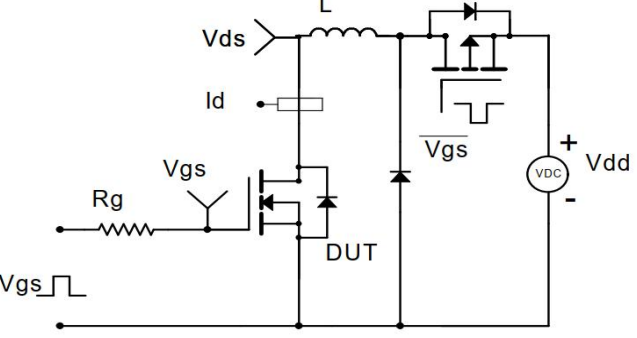
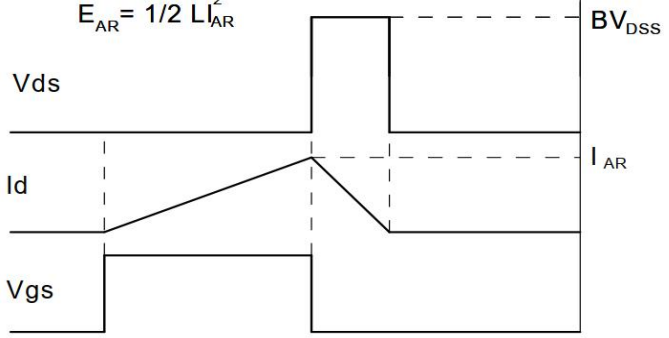
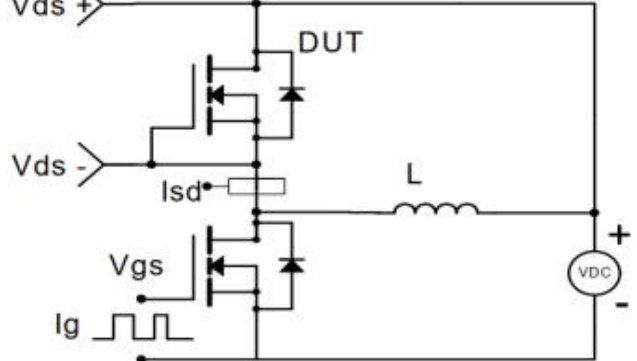
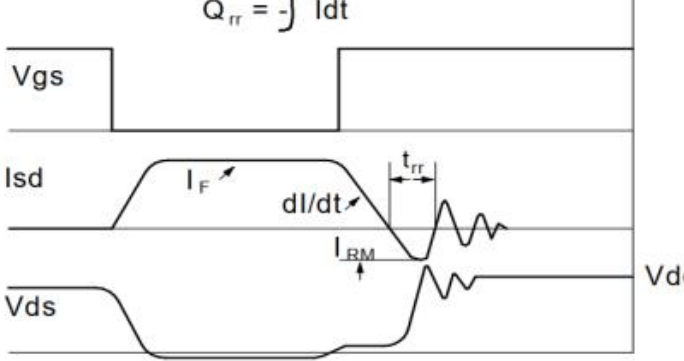


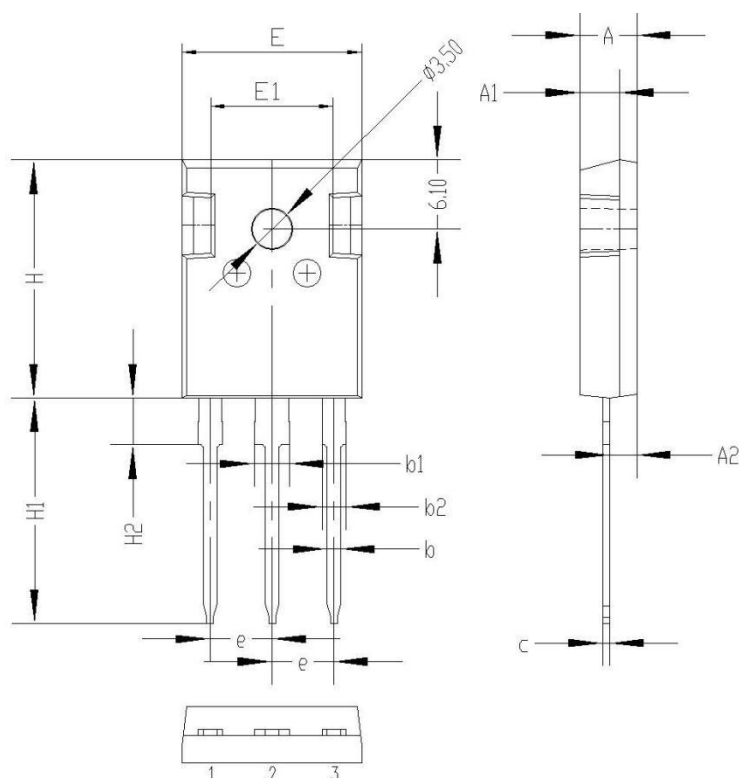
Figure 11 Normalized Maximum Transient Thermal Impedance



Test Circuit and Waveform

Gate Charge Test Circuit	Gate Charge Test Waveform
 <p>The diagram shows a MOSFET (DUT) with its gate connected to a pulse generator (Vgs) through a gate resistor (Rg). The drain is connected to a load resistor (RL) and a DC source (Vds). The gate current (Ig) is also indicated.</p>	 <p>The graph plots Vgs against Charge. It shows a linear ramp up to a plateau at 10V, followed by a linear ramp down. The total area under the curve is labeled Qg. The area under the rising ramp is Qgs, and the area under the falling ramp is Qgd.</p>
Resistive Switching Test Circuit	Resistive Switching Test Waveforms
 <p>The diagram shows a MOSFET (DUT) with its gate connected to a pulse generator (Vgs) through a gate resistor (Rg). The drain is connected to a load resistor (RL) and a DC source (Vdd). The drain-source voltage (Vds) is indicated.</p>	 <p>The graph shows Vds and Vgs waveforms. Vgs is a square wave with rise time tr, fall time tf, and total on/off times ton/toff. Vds is a trapezoidal wave with 90% and 10% voltage levels. The delay times td(on) and td(off) are also shown.</p>
Unclamped Inductive Switching (UIS) Test Circuit	Unclamped Inductive Switching (UIS) Test Waveforms
 <p>The diagram shows a MOSFET (DUT) with its gate connected to a pulse generator (Vgs) through a gate resistor (Rg). The drain is connected to an inductor (L) and a diode. The drain-source voltage (Vds) and drain current (Id) are indicated.</p>	 <p>The graph shows Vds, Id, and Vgs waveforms. Vgs is a square wave. Id is a triangular wave during the on-time. Vds shows a voltage spike during the off-time. The energy equation is given as $E_{AR} = 1/2 L I_{AR}^2$. The peak Vds is labeled BV_{DSS} and the peak Id is labeled I_{AR}.</p>
Diode Recovery Test Circuit	Diode Recovery Test Waveforms
 <p>The diagram shows a MOSFET (DUT) with its gate connected to a pulse generator (Vgs) through a gate resistor (Rg). The drain is connected to an inductor (L) and a diode. The drain-source voltage (Vds) and drain current (Isd) are indicated.</p>	 <p>The graph shows Vgs, Isd, and Vds waveforms. Vgs is a square wave. Isd is a trapezoidal wave with forward current IF and reverse current I_{RM}. Vds shows a reverse recovery spike. The reverse recovery time trr is indicated. The equation $Q_{rr} = \int Idt$ is shown.</p>

Package Description



Symbol	Unit mm		
	Min	Typ	Max
A	4.8	5.00	5.20
A1	3.3	3.5	3.7
A2	2.20	2.40	2.60
b	1.00	1.2	1.40
b1	2.90	3.10	3.30
b2	1.80	2.00	2.20
c	0.50	0.60	0.70
e	5.25	5.45	5.65
E	15.2	15.7	16.2
H	20.8	21	21.2
H1	19.5	20.0	20.5
H2	3.9	4.1	4.3
G	5.9	6.1	6.3
ΦP	3.30	3.50	3.70



NOTE:

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. MOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. Shenzhen Minos reserves the right to make changes in this specification sheet and is subject to change without prior notice.

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